

10063295-061202

1063295-061202

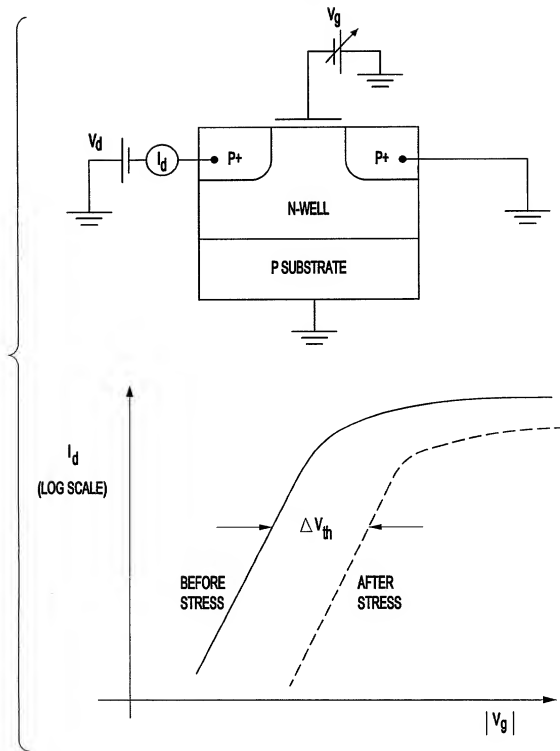
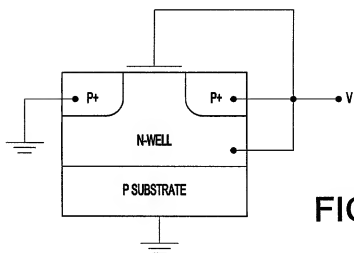
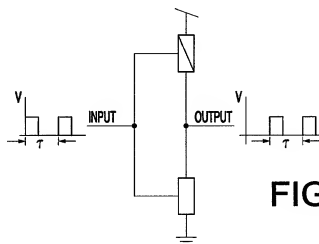
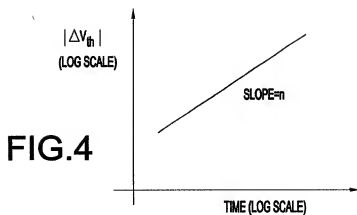


FIG.3



100632295-061202

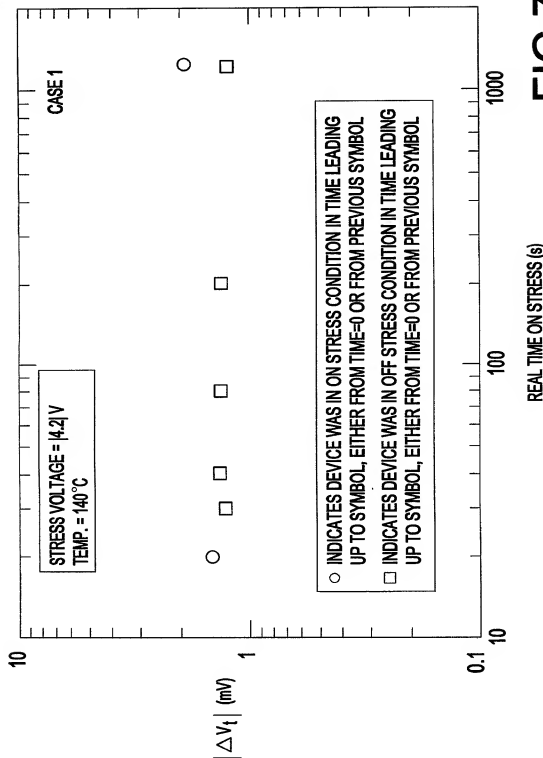
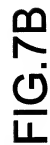


FIG.7A



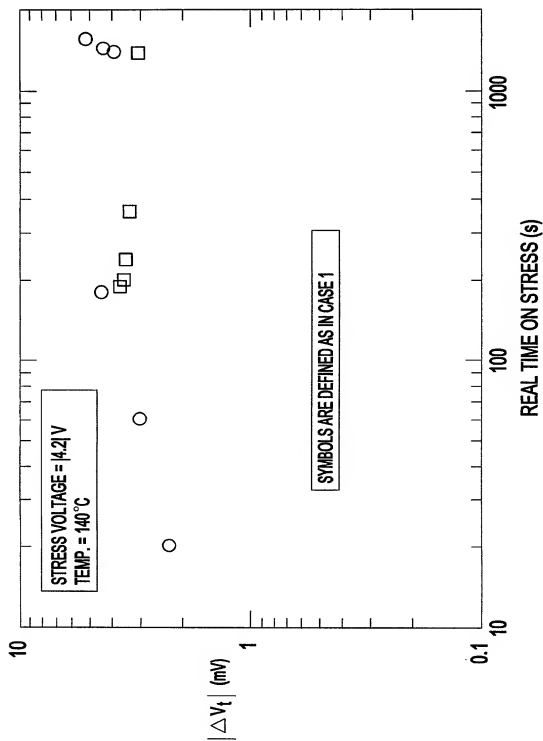


FIG.8A

202190' 56229001

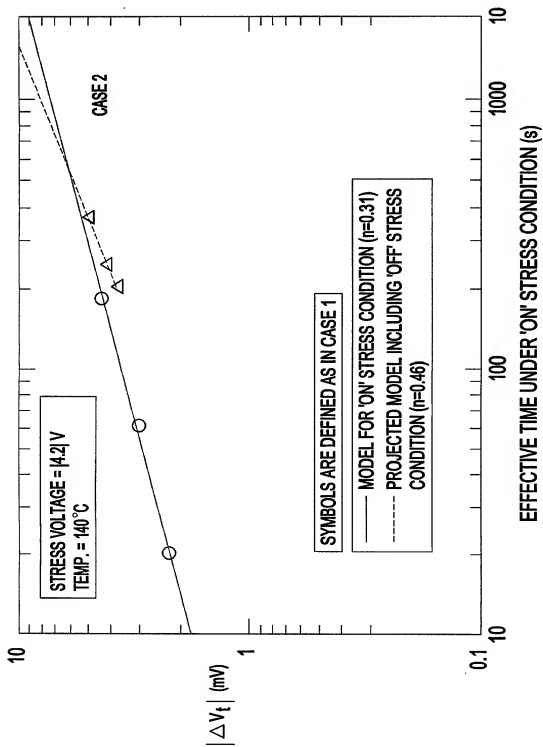


FIG.8B

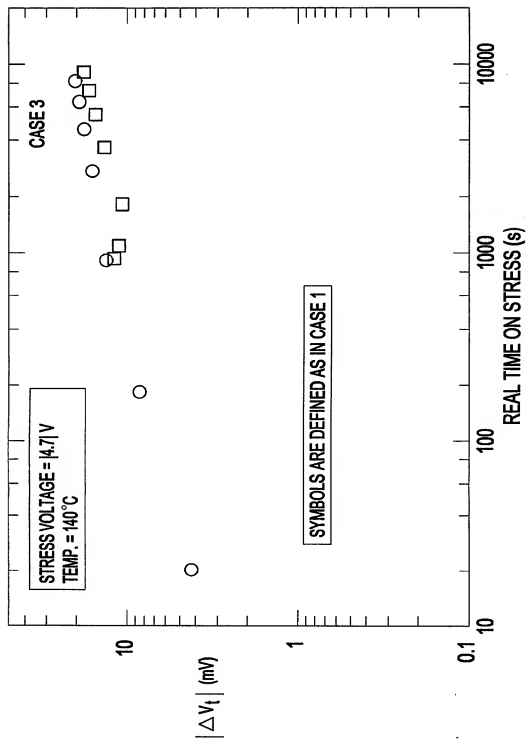


FIG.9A



202190-5625001

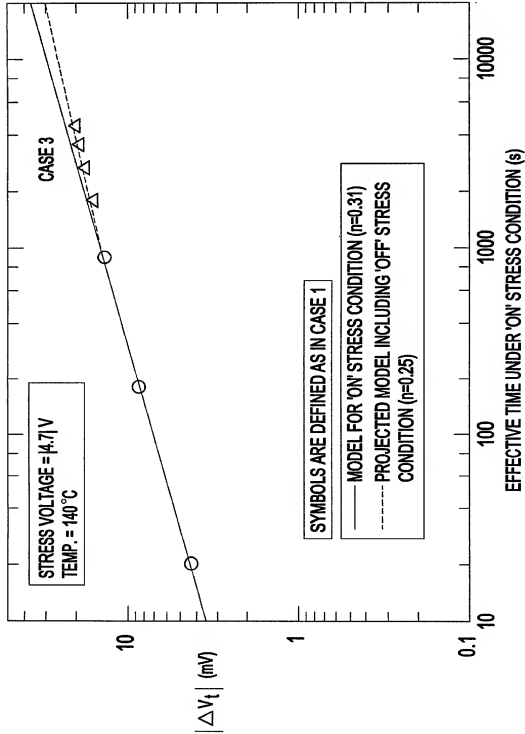


FIG.9B

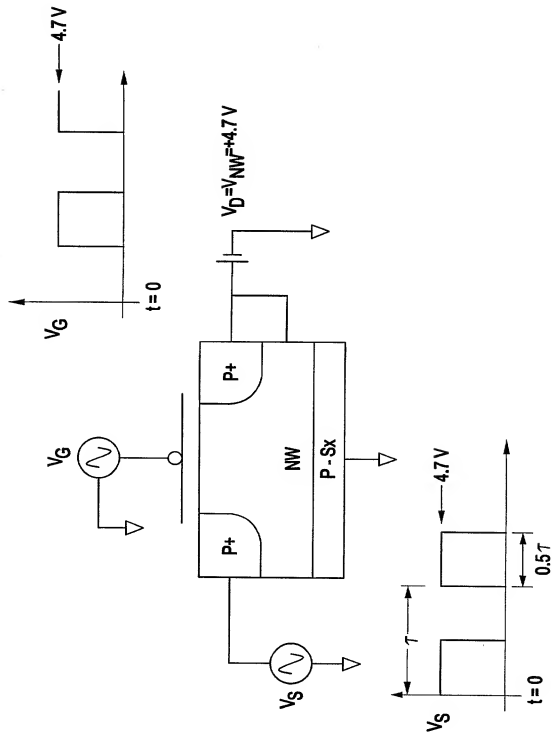


FIG.10

202150' 56239001

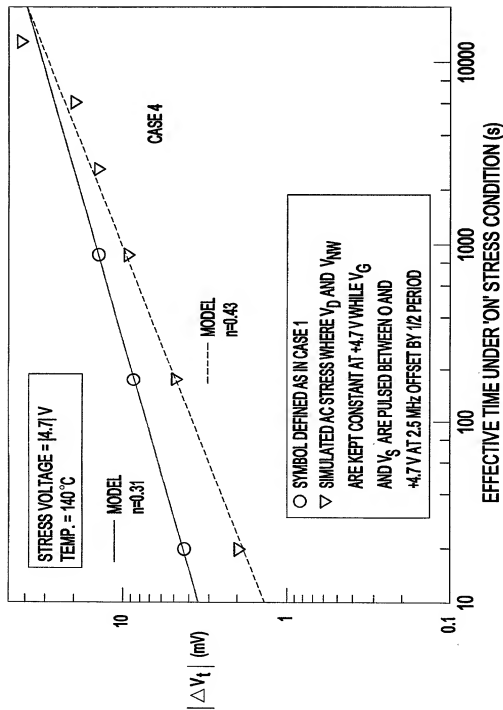
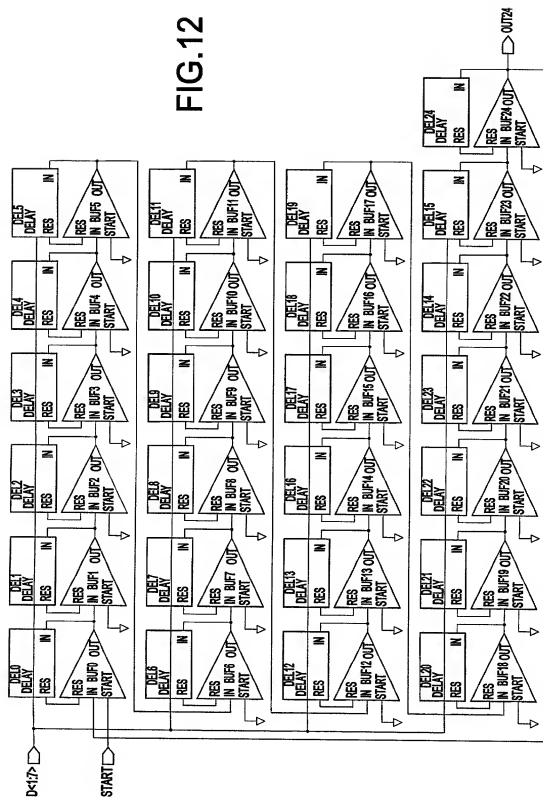


FIG.11

FIG.12



202190-502290T

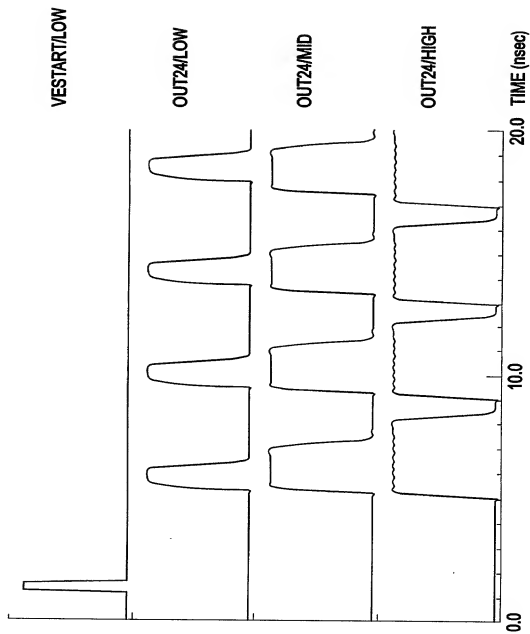
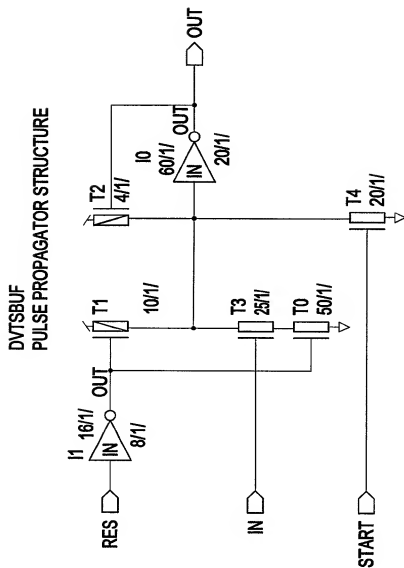


FIG.13



**FIG.14**

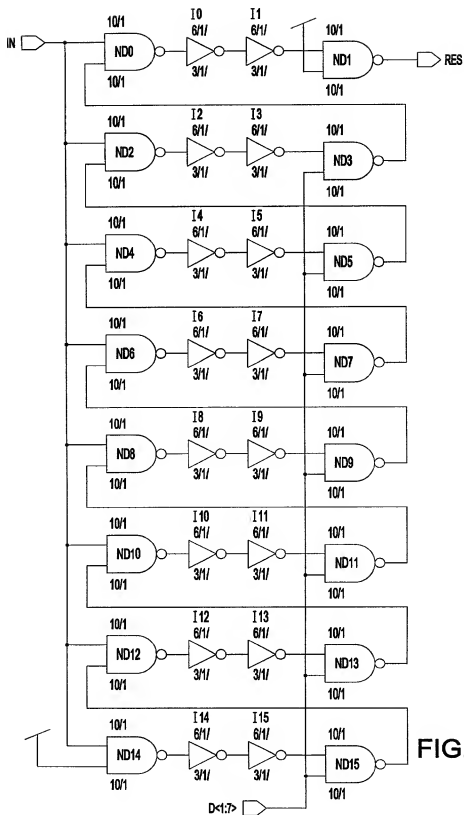


FIG.15

INPUT	FREE RUN	AC STRESS	DC STRESS
SOURCE	VDD	VDD	VDD/GND
GATE	GND	"A.C."	VDD/GND
VPP	VPP	VPP	VPP
bSTRESS1	VDD	VDD	GND
IN	"A.C."	GND	GND
DRAIN	VDD	VDD	VDD/GND
bSTRESS2	VPP	GND	GND

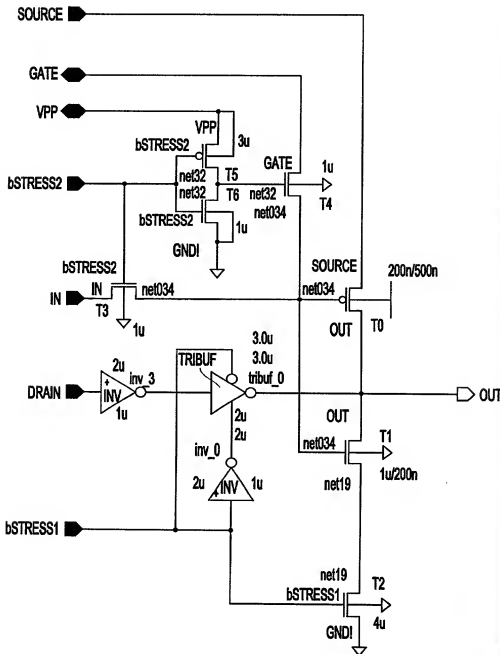


FIG.16



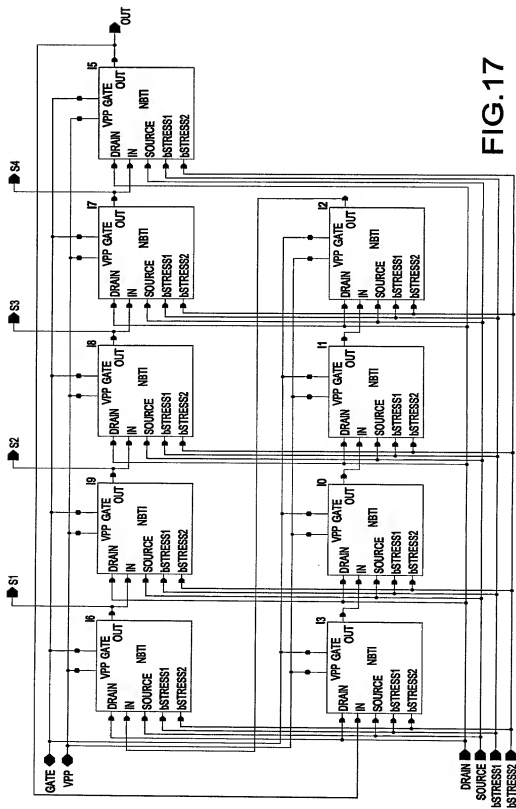


FIG. 17

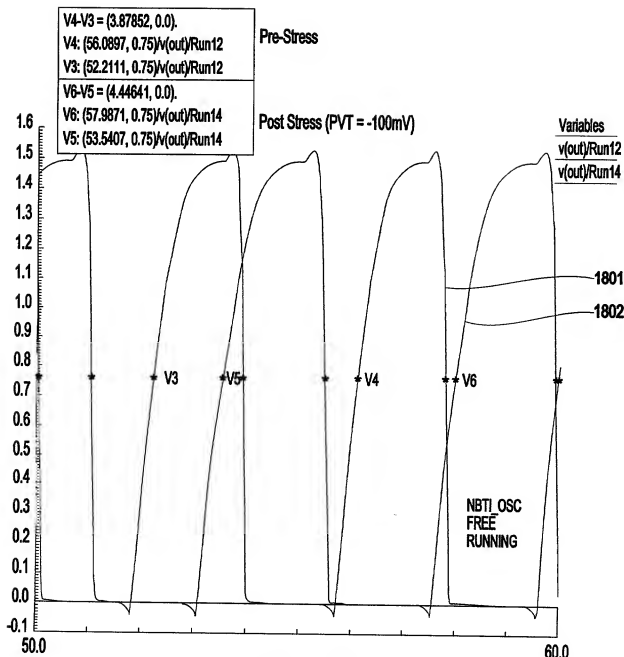


FIG.18

**FIG.19**

APPLICATION OF PFET DC STRESS IN RING OSCILLATOR  
AND DETERMINING DEGRADATION CONSTANTS

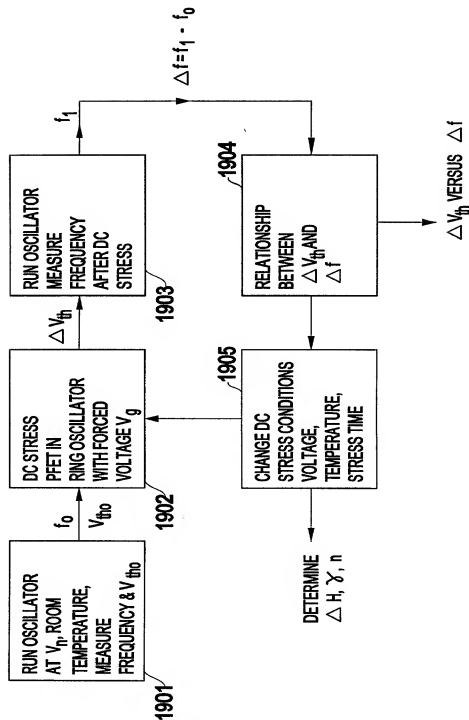
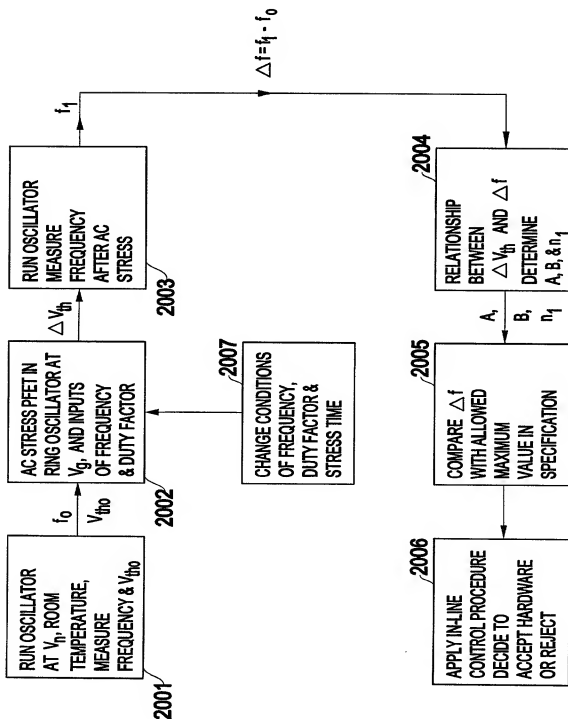


FIG.20



202190\*56229001